

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Han-Gu Sohn et al.

Examiner: Dare, Ryan A.

Serial No.: 10/732,868

Group: Art Unit 2186

Filed: December 10, 2003

Docket: 8729-226 (SS-20062-US)

**For: CIRCUITS AND METHODS FOR PROVIDING VARIABLE DATA I/O
 WIDTH FOR SEMICONDUCTOR MEMORY DEVICES**

Commissioner of Patents
P.O. Box 1450
Alexandria, VA. 22313-1450

Amendment

This is a response to the Final Office Action mailed on April 6, 2007. An RCE (Request for Continued Examination) is submitted herewith. The claims are amended as follows: